



Application Serial No. 09/844,175  
Filing Date April 27, 2001  
Inventorship Warren M. Farnworth et al.  
Assignee Micron Technology, Inc.  
Group Art Unit 2858  
Examiner R. Kobert  
Attorney's Docket No. MI22-1703  
Title: Removable Electrical Interconnect Apparatuses and Removable Engagement Probes

INTERVIEW SUMMARY

EV0 77331595

Applicants wish to thank the Examiner for the courtesies extended to the undersigned during the telephonic interview of August 8, 2002. The undersigned and the Examiner discussed the limitations of claims 31, 32 and claim 54. Applicants requested clarification of the teachings relied upon by the Examiner in support of the rejection of such claims, and in particular, structure of Blonder considered to anticipate the claimed substrate, engagement probe, and projection of claim 32. No agreement was reached regarding the patentability of any additional claims and it was agreed that Applicants would submit a response which accompanies this interview summary and further details the discussions between the undersigned and the Examiner.

The Examiner is requested to phone the undersigned if the Examiner believes such would facilitate prosecution of the present application. The undersigned is available for telephone consultation at any time during normal business hours (Pacific Time Zone).

Respectfully submitted,

Dated: \_\_\_\_\_

8/12/02

By: \_\_\_\_\_

James D. Shaurette  
Reg. No. 39,833

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